


<b>Search Notes</b>  	<b>Application/Control No.</b>  10585717	<b>Applicant(s)/Patent Under Reexamination</b>  LEPPERT ET AL.
	<b>Examiner</b>  Michael Pak	<b>Art Unit</b>  1646

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
East - search USPT, PGPUB, DWPI, EPAB, JPAB	6-16-09	MDP
STIC seq search - score	5-2-09	MDP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	See search notes	6-16-09	MDP

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